

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10638397	CHANG, LIN-WEI
	Examiner Kosowski, Alexander J	Art Unit 2125

SEARCHED			
Class	Subclass	Date	Examiner
700	90	12/20/07	AJK
361	685,727		

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST Search (attached)	12/20/07	AJK	
EIC TC2100 PLUS Search			
Consulted Primary Examiner in AU2835 for search assistance			
PALM Inventor Name Search			

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner